Cold electronics and DAPHNE for FD1-HD and FD2-VD

7 November 2022

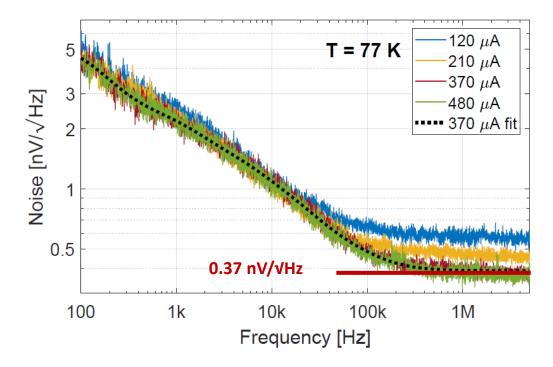
C. Gotti INFN/Univ. Milano-Bicocca

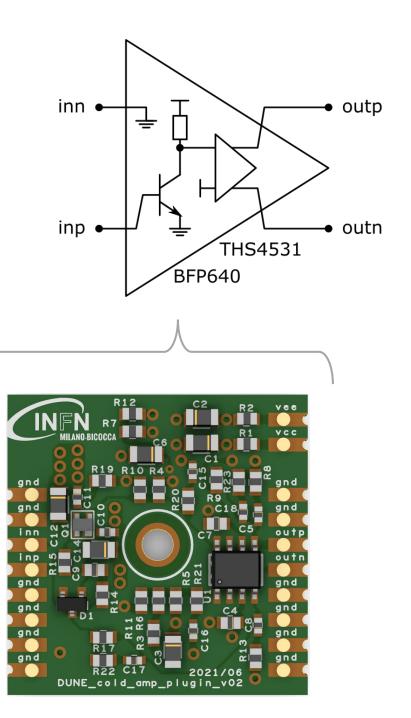
On behalf of the DUNE FD1 PD Photosensors & Electronics WGs

Cold amplifier for FD1-HD (1)

- Pseudo-differential configuration based on discrete commercial components
- **BFP640 SiGe bipolar transistor** for low series noise at low bias current (0.37 nV/VHz @ Ic=0.4 mA)
- THS4531 differential opamp for high loop gain & differential outputs

→ P. Carniti et al 2020 doi:10.1088/1748-0221/15/01/P01008
 → C. Brizzolari et al 2022 arXiv:2207.13616



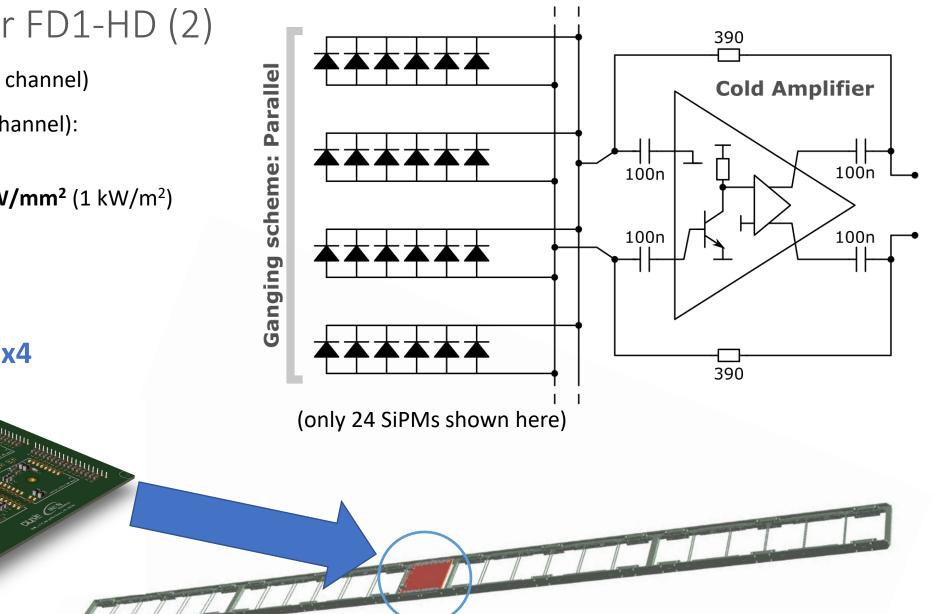


Cold amplifier for FD1-HD (2)

- Dimensions: 3x3 cm² (one channel)
- Total power at cold (one channel):
 0.7 mA x 3.3 V ≈ 2.4 mW

ARTIGUERAL MARTINE

 Max power density < 1mW/mm² (1 kW/m²) avoids LAr bubbling



=3 cm

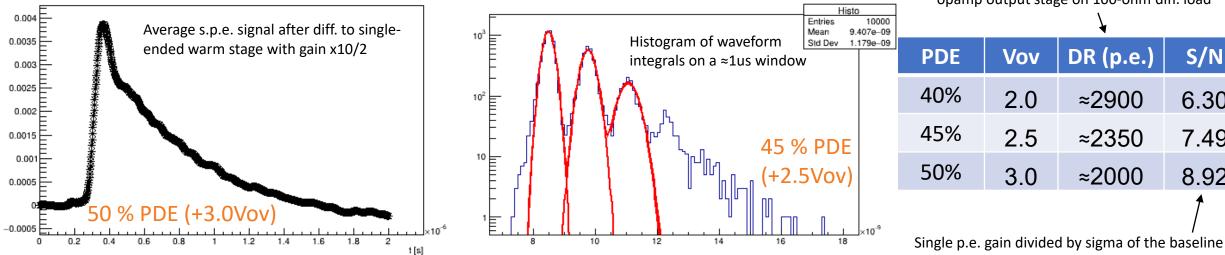
Cold amplifier for FD1-HD (3)

FD1-HD configuration, 48 SiPMs in parallel ٠

Hamamatsu 75um HRQ

Requirements:

- ≈2000 p.e. dynamic range
- <100 ns signal rise time
- S/N>4



Dynamic range before saturation of the opamp output stage on 100-ohm diff. load

Vov

2.0

2.5

3.0

DR (p.e.)

≈2900

≈2350

≈2000

S/N

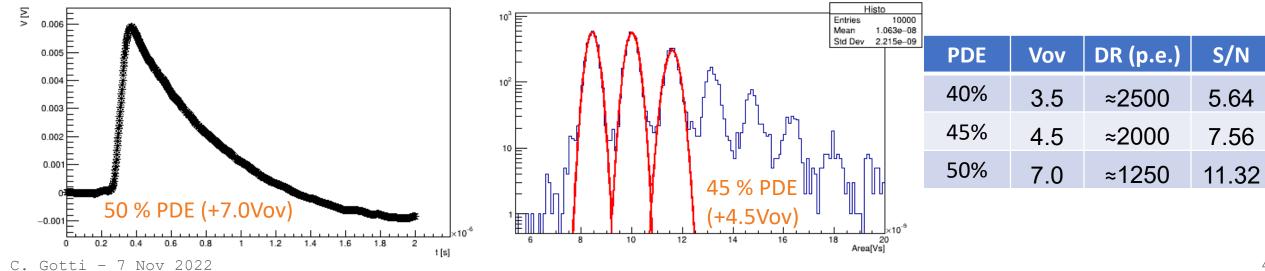
6.30

7.49

8.92

S/N

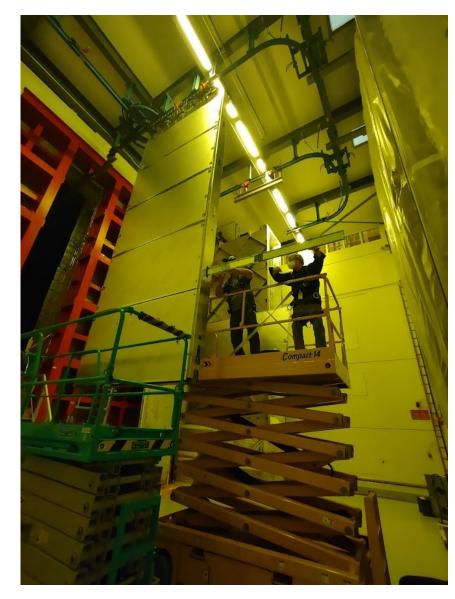
FBK 50um TT



Cold amplifier for FD1-HD (4)

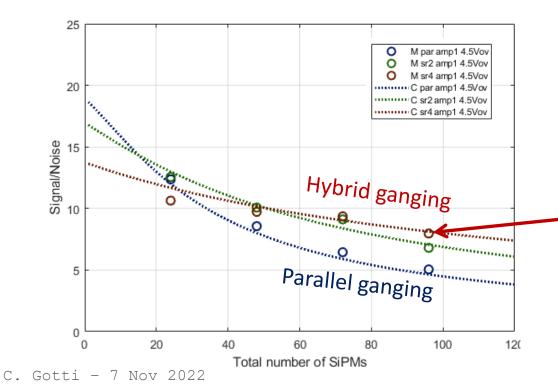
- Design tested in several labs and used for all supercell tests
- 160 chanels produced and installed in ProtoDUNE2
- Possible change for DUNE: 4 channels on one PCB instead of 4x single channel plugins on a motherboard (simpler and lower cost, although less flexible)

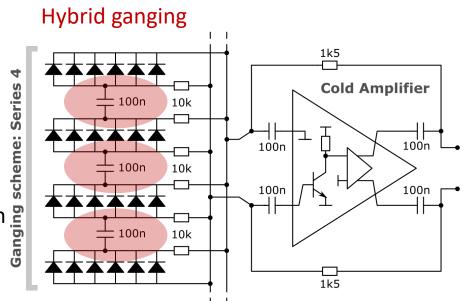


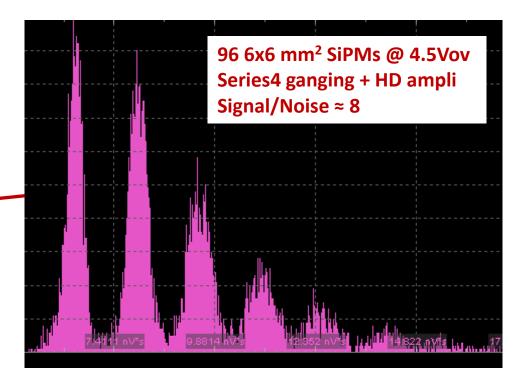


Cold amplifier for FD2-VD

- HD amplifier tested reading out up to 96 SiPMs (with HD SiPM boards)
 - S/N = 5 with 96 SiPMs in parallel
 - S/N = 8 in hybrid ganging (combination of parallel / AC series)
- Tests with VD flex SiPM boards to happen ≈next week
- Plan to readout ≈4 membrane ARAPUCAs (8 channels, 80 SiPMs each) in ProtoDUNE-VD
- Tests with the full «cathode» setup (PoF, SoF, DCDC, ...) also planned







Lifetime of components at cryo T

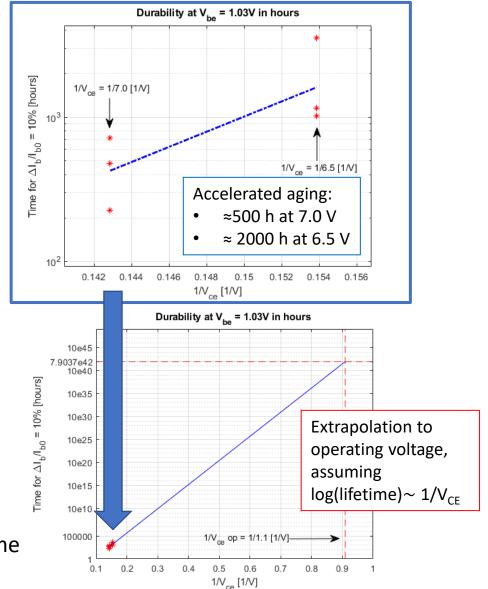
- At cryogenic temperature, increased carrier mobility can enhance degradation due to hot carrier effects (HCE)
- Aging accelerated by operation at high voltage (above max rating)
 → Li et al IEEE TNS doi:10.1109/TNS.2013.2287156
 → Cressler, Mantooth, Extreme Environment Electronics ISBN 9781138074224

BFP640 SiGe transistor

- Maximum datasheet values (room T): V_{CE}=4.1 V, I_C=50 mA
- Operated at V_{CE} =1.1 V, I_C =0.4 mA \rightarrow Ample margin
- Stressed up to V_{CE}=7.0 V
- Degradation criterion: 10% increase in base current (decrease in beta)
- Lifetime at the operating point extrapolated to very high values

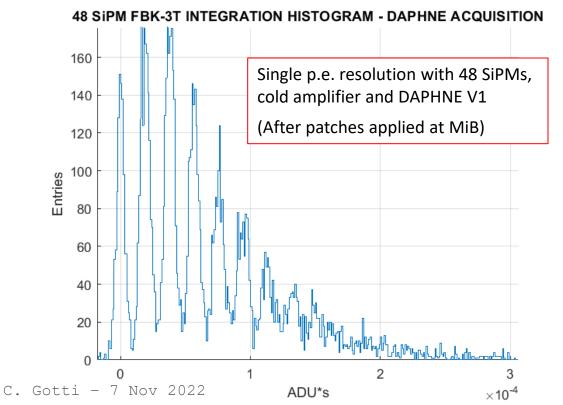
THS4531 fully differential opamp

- Maximum datasheet values (room T): V_s = 5.5 V
- Operated at $V_s = 3.3 V \rightarrow Ample margin$
- Stressed for HCE up to V_s =8.0 V
- Preliminary results at INFN LNS (P. Litrico et al) indicate very long lifetime



DAPHNE for FD1-HD

- 40-channel warm digitizer board developed by Fermilab and several institutions in Latin America (Colombia, Paraguay, Peru)
- Version 1 available since ≈ end of 2021, extensively tested in different labs
- Firmware in advanced state of development, integration with DAQ in progress at CERN
- Analog performance thoroughly characterized at MiB (E. Cristaldo), led to revised version DAPHNE V2A
- DAPHNE V2A produced (10 boards), currently under test at CERN and soon to be received at MiB and other labs





DAPHNE for FD2-VD

- A modified version of DAPHNE is planned to be used in the VD
- All «back-end» (digitization, trigger, interface with DAQ, data transmission, ...) can probably be reused without changes
- The «front-end» (signal conditioning before digitization) must be adapted
 - For cathode tiles, the SoF optical receiver needs to be added at the input
 - For membrane tiles, changes can be tested to remove/reduce signal undershoot related with differential to singleended conversion (currently done with a LAN transformer)

